

EMC TEST REPORT
For

Dong Guan Go Intel Electronics Technology CO.,LTD

Wired keyboard

Model No.: KB1280E

Additional Model No.: N/A

Prepared for : Dong Guan Go Intel Electronics Technology CO.,LTD
Address : Room 501, Building 4, No. 61, Gongao Heng 2nd
Road, Dalang Town, Dongguan City, Guangdong
Province

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Date of receipt of test sample : May 29, 2025
Number of tested samples : 1
Serial number : Prototype
Date of Test : May 29, 2025 - June 6, 2025
Date of Report : June 6, 2025



EMC TEST REPORT**EN 55032:2015+A11:2020**

Electromagnetic compatibility of multimedia equipment - Emission requirements

EN 55035:2017+A11:2020

Information technology equipment-Immunity characteristics-Limits and methods of measurement

Report Reference No.: AOC250606101E

Date Of Issue.....: June 6, 2025

Testing Laboratory Name.....: Shenzhen AOCE Electronic Technology Service Co., Ltd.

Address.....: Room 202, 2nd Floor, No.12th Building of Xinhe Tongfuyu Industrial Park, Fuhai Street, Baoan District, Shenzhen, Guangdong, China

Testing Location/ Procedure.....: Full application of Harmonised standards ☒
Partial application of Harmonised standards ☐
Other standard testing method ☐**Applicant's Name.....: Dong Guan Go Intel Electronics Technology CO.,LTD**

Address.....: Room 501, Building 4, No. 61, Gongao Heng 2nd Road, Dalang Town, Dongguan City, Guangdong Province

Test Specification:Standard.....: EN 55032:2015+A11:2020
EN IEC 61000-3-2:2019+A1:2021+A2:2024
EN 61000-3-3:2013+A1:2019+A2:2021+AC:2022
EN 55035:2017+A11:2020

Test Report Form No.....: AOCEMC-1.0

TRF Originator.....: Shenzhen AOCE Electronic Technology Service Co., Ltd.

Master TRF.....: Dated 2011-03

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Test Item Description.....: Wired keyboard

Trade Mark.....: N/A

Model/ Type Reference.....: KB1280E

Ratings.....: 5V, 6MHZ, 100mA, 0.5W

Result: Positive**Compiled by:**

David Liu

David Liu/ File administrators

Supervised by:

Kevin Huang

Kevin Huang/ Technique principal

Approved by:

Jackson Fang

Jackson Fang/ Manager

EMC -- TEST REPORT

Test Report No. : AOC250606101EJune 6, 2025

Date of issue

Type / Model..... : KB1280E

EUT..... : Wired keyboard

Applicant..... : Dong Guan Go Intel Electronics Technology CO.,LTDAddress..... : Room 501, Building 4, No. 61, Gongao Heng 2nd Road,
Dalang Town, Dongguan City, Guangdong Province

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Dalang Town, Dongguan City, Guangdong Province

Telephone..... : /

Fax..... : /

Test Result according to the standards on page 6: **Pass**

The test report merely corresponds to the test sample.

It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

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1. SUMMARY OF STANDARDS AND RESULTS

1.1. Description of Standards and Results

The EUT have been tested according to the applicable standards as referenced below.

EMISSION (EN 55032:2015+A11:2020)			
Description of Test Item	Standard	Limits	Results
Conducted disturbance at mains terminals	EN 55032:2015+A11:2020	Class B	N/A
Conducted disturbance at telecommunication port	EN 55032:2015+A11:2020	Class B	N/A
Radiated disturbance	EN 55032:2015+A11:2020	Class B	PASS
Harmonic current emissions	EN IEC 61000-3-2: 2019+A1: 2021+A2: 2024	Class A	N/A
Voltage fluctuations & flicker	EN 61000-3-3: 2013+A1: 2019+A2: 2021+AC: 2022	-----	N/A
IMMUNITY(EN 55035: 2017+A11:2020)			
Description of Test Item	Basic Standard	Performance Criteria	Results
Electrostatic discharge (ESD)	EN 61000-4-2: 2009	B	PASS
Radio-frequency, Continuous radiated disturbance	EN 61000-4-3: 2020	A	PASS
Electrical fast transient (EFT)	EN 61000-4-4: 2012	B	N/A
Surge (Input a.c. power ports)	EN 61000-4-5: 2014+A1: 2017	B	N/A
Surge (Telecommunication ports)		B	N/A
Radio-frequency, Continuous conducted disturbance	EN 61000-4-6: 2014+AC: 2015	A	N/A
Power frequency magnetic field	EN 61000-4-8: 2010	A	PASS
Voltage dips, >95% reduction	EN 61000-4-11: 2020	B	N/A
Voltage dips, 30% reduction		B	N/A
Voltage interruptions		C	N/A
N/A is an abbreviation for Not Applicable.			

1.2. Description of Performance Criteria

General Performance Criteria

Examples of functions defined by the manufacturer to be evaluated during testing include, but are not limited to, the following:

- essential operational modes and states;
- tests of all peripheral access (hard disks, floppy disks, printers, keyboard, mouse, etc.);
- quality of software execution;
- quality of data display and transmission;
- quality of speech transmission.

1.2.1. Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

1.2.2. Performance criterion B

After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacture, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operation state or stored data is allowed to persist after the test.

If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

1.2.3. Performance criterion C

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacture's instructions.

Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

2. GENERAL INFORMATION

2.1. Description of Device (EUT)

EUT : Wired keyboard

Model Number : KB1280E

Power Supply : 5V, 6MHZ, 100mA, 0.5W

EUT Clock Frequency : $\leq$ 108MHz

2.2. Description of Test Facility

Site Description
EMC Lab.

2.3. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. To CISPR 16 – 4 “Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements” and is documented in the AOCE quality system acc. To DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

2.4. Measurement Uncertainty

Test Item		Frequency Range	Uncertainty	Note
Radiation Uncertainty	:	30MHz~200MHz	$\pm 2.96\text{dB}$	(1)
		200MHz~1000MHz	$\pm 3.10\text{dB}$	(1)
Conduction Uncertainty	:	150kHz~30MHz	$\pm 1.63\text{dB}$	(1)
Power disturbance	:	30MHz~300MHz	$\pm 1.60\text{dB}$	(1)

(1). This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3. MEASURING DEVICES AND TEST EQUIPMENT

3.1. Conducted Disturbance

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2024/4/13
2	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2024/4/13
3	Artificial Mains	ROHDE & SCHWARZ	ENV216	101288	2024/4/13
4	EMI Test Software	AUDIX	E3	N/A	2024/4/13

3.2. Disturbance Power

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2024/4/13
2	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2024/4/13
3	Absorbing clamp	ROHDE & SCHWARZ	MDS 21	4033	2024/4/13
4	EMI Test Software	AUDIX	E3	N/A	2024/4/13

3.3. Radiated Electromagnetic Disturbance

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2024/4/13
2	Triple-loop Antenna	EVERFINE	LLA-2	11050003	2024/4/13
3	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2024/4/13
4	EMI Test Software	AUDIX	E3	N/A	2024/4/13

3.4. Radiated Disturbance (Electric Field)

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2024/4/13
2	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2024/4/13
3	Log per Antenna	SCHWARZBECK	VULB9163	9163-470	2024/4/13
4	Amplifier	Compliance Direction	PAP-0102	21001	2024/4/13
5	EMI Test Software	AUDIX	E3	N/A	2024/4/13

3.5. Harmonic Current

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power Analyzer Test System	Voltech	PM6000	20000670053	2024/4/13

3.6. Voltage fluctuation and Flicker

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power Analyzer Test System	Voltech	PM6000	20000670053	2024/4/13

3.7.Electrostatic Discharge

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	ESD Simulator	KIKUSUI	KC001311	KES4021	2024/4/13

3.8.RF Field Strength Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	SIGNAL GENERATOR	HP	8648A	625U00573	2024/4/13
2	Amplifier	AR	500A100	17034	2024/4/13
3	Amplifier	AR	100W/1000M 1	17028	2024/4/13
4	Isotropic Field Monitor	AR	FM2000	16829	2024/4/13
5	Isotropic Field Probe	AR	FP2000	16755	2024/4/13
6	Bi-conic Antenna	EMCO	3108	9507-2534	2024/4/13
7	By-log-periodic Antenna	AR	AT1080	16812	2024/4/13
8	EMS Test Software	ROHDE & SCHWARZ	ESK1	N/A	2024/4/13

3.9.Electrical Fast Transient/Burst

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Electrical fast transient(EFT)generator	3CTEST	EFT-4021	EC0461044	2024/4/13
2	Coupling Clamp	3CTEST	EFTC	EC0441098	2024/4/13

3.10.Surge

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Surge test system	3CTEST	SG-5006G	EC5581070	2024/4/13
2	Coupling/decoupling network	3CTEST	SGN-5010G	ECS5591033	2024/4/13

3.11.Conducted Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Conducted Immunity Test System	FRANKONIA	CIT-10	126A1195	2024/4/13
2	Coupling/decoupling network	FRANKONIA	CDN-M2+M3	A2210177	2024/4/13

3.12.Power Frequency Magnetic Field Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power frequency mag-field generator System	EVERFINE	EMS61000-8 K	906003	2024/4/13

3.13.Voltage Dips

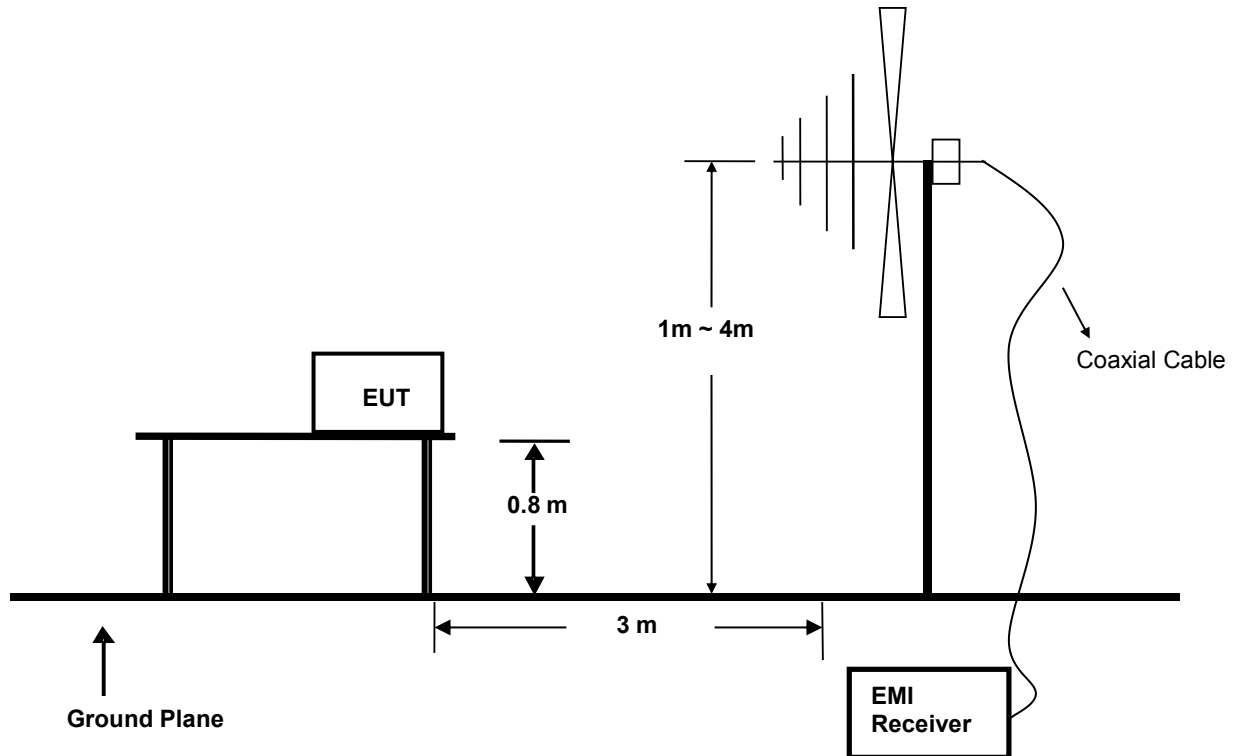
Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Voltage dips and up generator	3CTEST	VDG-1105G	EC0171014	2024/4/13

3.14.Voltage Short Interruptions

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Voltage dips and up generator	3CTEST	VDG-1105G	EC0171014	2024/4/13

4. RADIATED EMISSION MEASUREMENT

4.1. Block Diagram of Test Setup



4.2. Measuring Standard

EN 55032:2015+A11:2020

4.3. Radiated Emission Limits

EN 55032 Limits:

All emanations from a class B device or system, including any network of conductors and apparatus connected thereto, shall not exceed the level of field strengths specified below:

FREQUENCY (MHz)	DISTANCE (Meters)	FIELD STRENGTHS LIMIT (dB μ V/m)
30 ~ 230	3	40
230 ~ 1000	3	47

Note: (1) The smaller limit shall apply at the combination point between two frequency bands.

(2) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the EUT.

4.4.EUT Configuration on Test

The EN 55032 regulations test method must be used to find the maximum emission during radiated emission measurement.

4.5.Operating Condition of EUT

4.5.1 Turn on the power.

4.5.2 After that, let the EUT work in test mode (ON) and measure it.

4.6.Test Procedure

The EUT is placed on a turntable, which is 0.8 meter high above the ground. The turntable can rotate 360 degrees to determine the position of the maximum emission level. The EUT is set 3 meters away from the receiving antenna, which is mounted on a antenna tower. The antenna can be moved up and down from 1 to 4 meters to find out the maximum emission level. By-log antenna is used as a receiving antenna. Both horizontal and vertical polarization of the antenna is set on test.

The bandwidth of the Receiver is set at 120kHz.

The frequency range from 30MHz to 1000MHz is investigated.

4.7.Test Results

PASS.

The test result please refer to the next page.

Model No.	KB1280E	Test Date	May 29, 2025
Environmental Conditions	24°C/ 56% RH	Test Mode	On
Pol	Vertical	Detector Function	Quasi-peak
Test Engineer	Andy	Distance	3m



Suspected List

Suspected List									
NO.	Freq. [MHz]	Factor [dB]	Reading [dBμV/m]	Level [dBμV/m]	Limit [dBμV/m]	Margin [dB]	Height [cm]	Angle [°]	Polarity
1	47.4775	-13.86	44.07	30.21	40.00	9.79	100	103	Vertical
2	172.7327	-16.77	41.19	24.42	40.00	15.58	100	266	Vertical
3	192.1522	-15.74	39.37	23.63	40.00	16.37	100	128	Vertical
4	397.9980	-9.55	42.08	32.53	47.00	14.47	100	59	Vertical
5	436.8368	-8.91	39.49	30.58	47.00	16.42	100	190	Vertical
6	610.6406	-5.36	29.99	24.63	47.00	22.37	100	165	Vertical

Model No.	KB1280E	Test Date	May 29, 2025
Environmental Conditions	24°C/ 56% RH	Test Mode	On
Pol	Horizontal	Detector Function	Quasi-peak
Test Engineer	Andy	Distance	3m

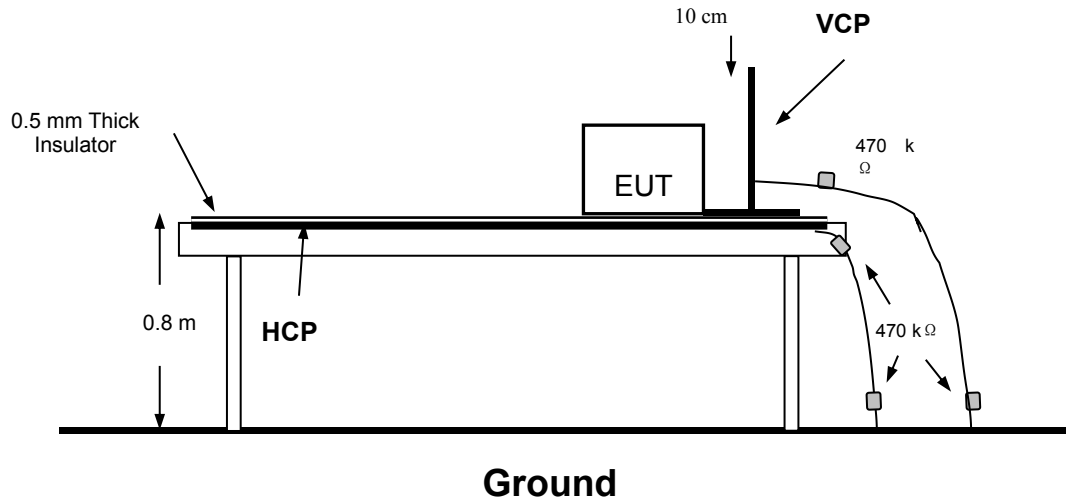


Suspected List

Suspected List									
NO.	Freq. [MHz]	Factor [dB]	Reading [dBμV/m]	Level [dBμV/m]	Limit [dBμV/m]	Margin [dB]	Height [cm]	Angle [°]	Polarity
1	47.4775	-13.86	41.97	28.11	40.00	11.89	100	145	Horizontal
2	132.9229	-17.24	38.93	21.69	40.00	18.31	100	160	Horizontal
3	174.6747	-16.85	44.88	28.03	40.00	11.97	100	218	Horizontal
4	297.9880	-11.79	37.95	26.16	47.00	20.84	100	5	Horizontal
5	403.8238	-9.83	40.82	30.99	47.00	16.01	100	192	Horizontal
6	435.8659	-8.99	43.03	34.04	47.00	12.96	100	273	Horizontal

5. ELECTROSTATIC DISCHARGE IMMUNITY TEST

5.1. Block Diagram of Test Setup



5.2. Test Standard

EN 55035: 2017+A11:2020,

Severity Level: 3 / Air Discharge: $\pm 8\text{KV}$, Level: 2 / Contact Discharge: $\pm 4\text{KV}$)

5.3. Severity Levels and Performance Criterion

5.3.1. Severity level

Level	Test Voltage Contact Discharge (KV)	Test Voltage Air Discharge (KV)
1.	± 2	± 2
2.	± 4	± 4
3.	± 6	± 8
4.	± 8	± 15
X	Special	Special

5.3.2. Performance Criterion: **B**

5.4. EUT Configuration on Test

The configuration of EUT is listed in Section 3.7.

5.5.Operating Condition of EUT

- 5.4.1.Setup the EUT as shown on Section 5.1.
- 5.4.2.Turn on the power of all equipments.
- 5.4.3.Let the EUT work in measuring mode (ON) and measure it.

5.6.Test Procedure

5.6.1.Air Discharge

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT.

After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed

5.6.2.Contact Discharge

All the procedure shall be same as Section 5.6.1. Except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

5.6.3.Indirect Discharge For Horizontal Coupling Plane

At least 10 single discharges (in the most sensitive polarity) shall be applied at the front edge of each HCP opposite the center point of each unit (if applicable) of the EUT and 0.1m from the front of the EUT. The long axis of the discharge electrode shall be in the plane of the HCP and perpendicular to its front edge during the discharge.

5.6.4.Indirect Discharge For Vertical Coupling Plane

At least 10 single discharge (in the most sensitive polarity) shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

5.7.Test Results

PASS.

Please refer to the following pages

Electrostatic Discharger Test Results

Standard	☐ IEC 61000-4-2 ☒ EN 61000-4-2		
Applicant	Dong Guan Go Intel Electronics Technology CO.,LTD		
EUT	Wired keyboard	Temperature	24℃
M/N	KB1280E	Humidity	53%
Criterion	B	Pressure	1021mbar
Test Mode	ON	Test Date	May 29, 2025
Test Engineer	Andy		

Air Discharge

Test Points	Test Levels			Results		
	± 2kV	± 4kV	± 8kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☒	☐	☐ A ☒ B
Back	☒	☒	☒	☒	☐	☐ A ☒ B
Left	☒	☒	☒	☒	☐	☐ A ☒ B
Right	☒	☒	☒	☒	☐	☐ A ☒ B
Top	☒	☒	☒	☒	☐	☐ A ☒ B
Bottom	☒	☒	☒	☒	☐	☐ A ☒ B

Contact Discharge

Test Points	Test Levels		Results		
	± 2 kV	±4 kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☐	☐ A ☒ B
Back	☒	☒	☒	☐	☐ A ☒ B
Left	☒	☒	☒	☐	☐ A ☒ B
Right	☒	☒	☒	☐	☐ A ☒ B
Top	☒	☒	☒	☐	☐ A ☒ B
Bottom	☒	☒	☒	☐	☐ A ☒ B

Discharge To Horizontal Coupling Plane

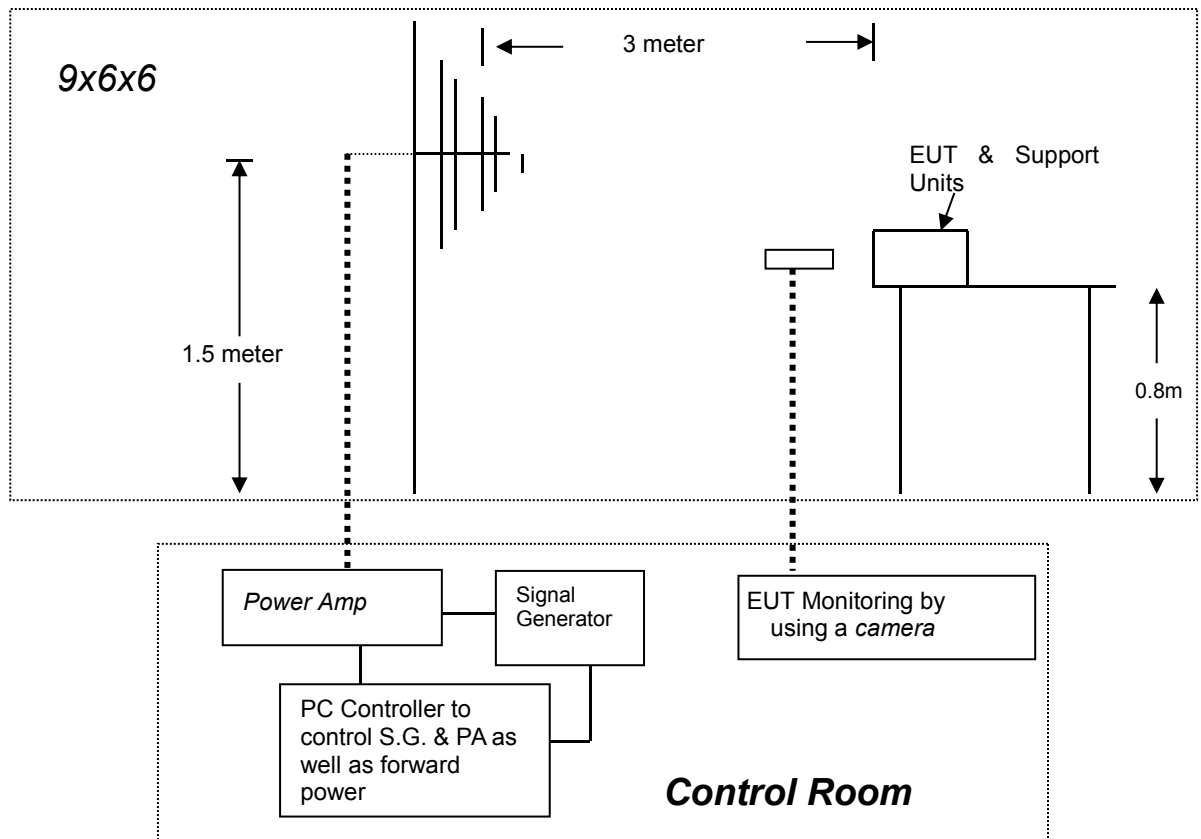
Side of EUT	Test Levels		Results		
	± 2 kV	± 4 kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☐	☐ A ☒ B
Back	☒	☒	☒	☐	☐ A ☒ B
Left	☒	☒	☒	☐	☐ A ☒ B
Right	☒	☒	☒	☐	☐ A ☒ B

Discharge To Vertical Coupling Plane

Side of EUT	Test Levels		Results		
	± 2 kV	± 4 kV	Passed	Fail	Performance Criterion
Front	☒	☒	☒	☐	☐ A ☒ B
Back	☒	☒	☒	☐	☐ A ☒ B
Left	☒	☒	☒	☐	☐ A ☒ B
Right	☒	☒	☒	☐	☐ A ☒ B

6. RF FIELD STRENGTH SUSCEPTIBILITY TEST

6.1. Block Diagram of Test



6.2. Test Standard

EN 55035: 2017+A11:2020,

(EN 61000-4-3: 2020 Severity Level: 2, 3V / m)

6.3. Severity Levels and Performance Criterion

6.3.1. Severity Levels

Level	Field Strength (V/m)
1.	1
2.	3
3.	10
X.	Special

6.3.2. Performance Criterion: A

6.4.EUT Configuration on Test

The configuration of the EUT is same as Section 3.8.

6.5.Operating Condition of EUT

Same as radiated emission measurement, which is listed in Section 4.5, except the test setup replaced as Section 6.1.

6.6.Test Procedure

The EUT are placed on a table, which is 0.8 meter high above the ground. The EUT is set 3 meters away from the transmitting antenna, which is mounted on an antenna tower. Both horizontal and vertical polarization of the antenna is set on test. Each of the four sides of the EUT must be faced this transmitting antenna and measured individually. In order to judge the EUT performance, a CCD Recording is used to monitor its screen. All the scanning conditions are as following:

Condition of Test	Remark
-----	-----
1. Fielded Strength	3V/m (Severity Level 2)
2. Radiated Signal	Unmodulated
3. Scanning Frequency	80-1000MHz
4. Sweep time of radiated	0.0015 Decade/s
5. Dwell Time	3 Sec.

6.7.Test Results

PASS.

Please refer to the following page.

RF Field Strength Susceptibility Test Results

Standard	☐ IEC 61000-4-3 ☒ EN 61000-4-3		
Applicant	Dong Guan Go Intel Electronics Technology CO.,LTD		
EUT	Wired keyboard	Temperature	24℃
M/N	KB1280E	Humidity	53%
Field Strength	3 V/m	Criterion	A
Test Mode	ON	Test Engineer	Andy
Frequency Range	80 MHz to 1000 MHz	Test Date	May 29, 2025
Modulation	☐ None ☐ Pulse ☒ AM 1KHz 80%		
Steps	1%		

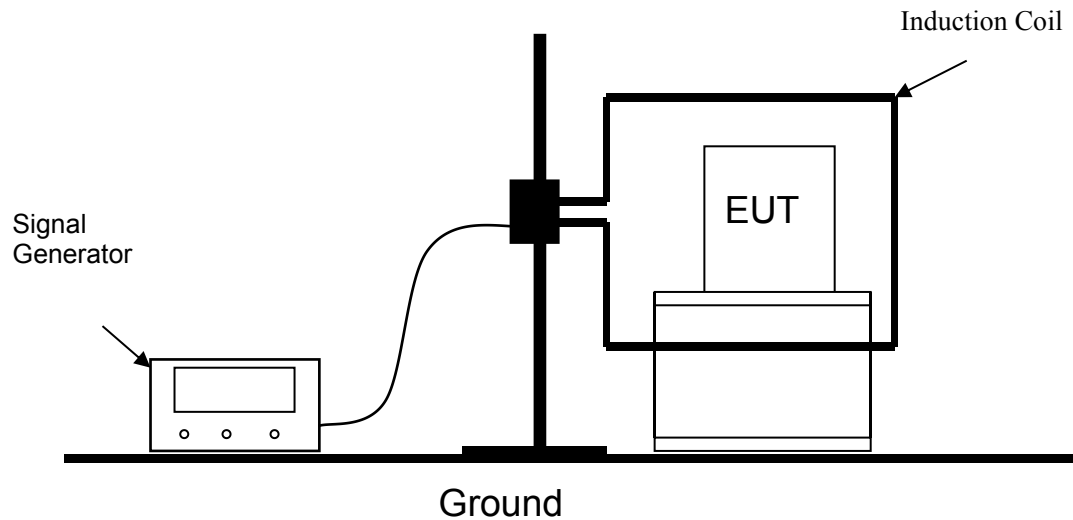
	Horizontal	Vertical
Front	PASS	PASS
Right	PASS	PASS
Rear	PASS	PASS
Left	PASS	PASS

Test Equipment:
1. Signal Generator: 2031 (MARCONI)
2. Power Amplifier: 500A100 & 100W/1000M1 (A&R)
3. Power Antenna: 3108 (EMCO) & AT1080 (A&R)
4. Field Monitor: FM2000 (A&R)

Note:

7. MAGNETIC FIELD SUSCEPTIBILITY TEST

7.1. Block Diagram of Test Setup



7.2. Test Standard

EN 55035: 2017+A11:2020,

(EN 61000-4-8: 2010, Severity Level: Level 1, 1A / m)

7.3. Severity Levels and Performance Criterion

7.3.1. Severity Levels

Level	Field Strength (A/m)
1	1
2	3
3	10
4	30
5	100
X	Special

7.3.2. Performance Criterion: A

7.4. EUT Configuration on Test

The configuration of the EUT is same as Section 3.12.

7.5. Test Procedure

The EUT is placed in the middle of a induction coil (1*1m), under which is a 1*1*0.1m (high) table, this small table is also placed on a larger table, 0.8 m above the ground. Both horizontal and vertical polarization of the induction coil is set on test, so that each side of the EUT is affected by the magnetic field. Also can reach the same aim by change the position of the EUT.

7.6. Test Results

PASS.

Please refer to the following page.

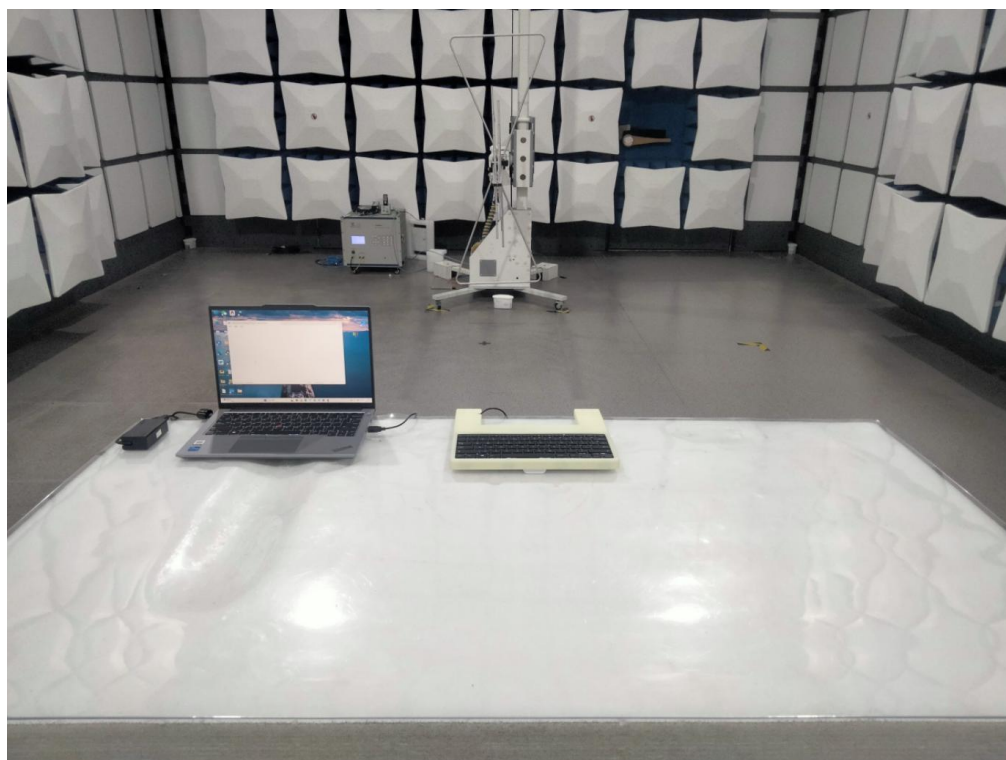
Magnetic Field Immunity Test Result			
Standard	☐ IEC 61000-4-8 ☒ EN 61000-4-8		
Applicant	Dong Guan Go Intel Electronics Technology CO.,LTD		
EUT	Wired keyboard	Temperature	24℃
M/N	KB1280E	Humidity	53%
Test Mode	ON	Criterion	A
Test Engineer	Andy	Test Date	May 29, 2025

Test Level (A/M)	Testing Duration	Coil Orientation	Criterion	Result
1	5 mins	X	A	PASS
1	5 mins	Y	A	PASS
1	5 mins	Z	A	PASS

Note:

8. PHOTOGRAPH

8.1. Photo of Radiated Measurement



9. EXTERNAL AND INTERNAL PHOTOS OF THE EUT



Fig.1

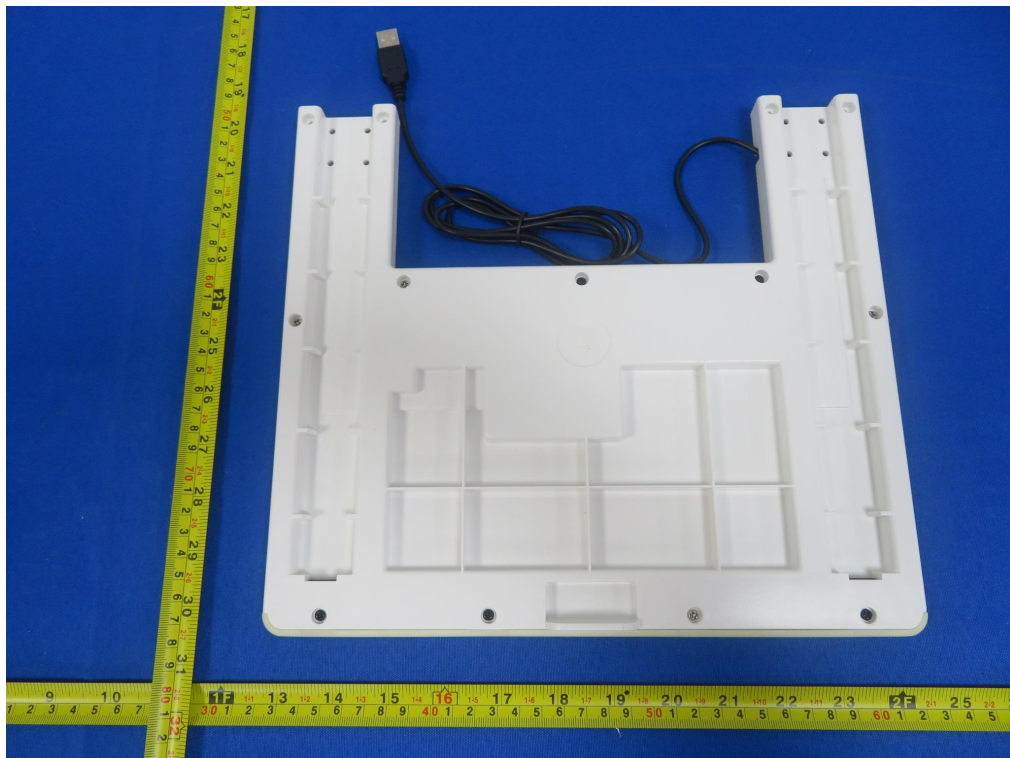


Fig.2

-----THE END OF REPORT-----